

VMDSEMI

VFPB004R013NA

Datasheet



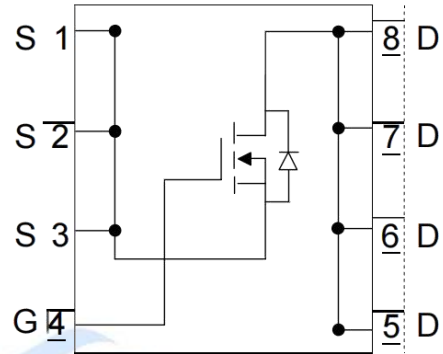
VMDSEMI

Description

- 40V N-channel SGT MOSFET
- It has been designed to ultra-low on-state resistance ($R_{DS(ON)}$) and yet maintain superior switching performance

$V_{(BR)DSS}$	$R_{DS(ON)_{max}}$	I_D
40V	1.3mΩ@10V	176A

Symbol



Symbol of VFPB004R013NA

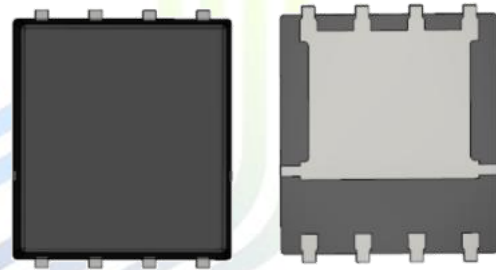
Features

- N-channel, optimized for high-speed smooth switching
- Excellent gate charge $\times R_{DS(ON)}$ (FOM)
- Ultra-low on-resistance
- Rohs compliant ^{Note 1}
- Halogen-free ^{Note 1}

Application

- DC-DC Conversion
- Power tools

Package Type



Package Type of VFPB004R013NA

Ordering Information

Product Name	Package
VFPB004R013NA	PDFN5×6

Absolute Maximum Ratings ($T_J = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Value	Units
Drain-Source Voltage	V_{DS}	40	V
Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	I_D	176	A
Drain Current - Continuous ($T_C = 100^\circ\text{C}$)		110	A
Drain Current - Pulsed ^{Note 1,2}	I_{DM}	550	A
Gate-Source Voltage	V_{GS}	± 20	V
Single Pulsed Avalanche Energy ^{Note 3}	E_{AS}	306	mJ
Power Dissipation ($T_C = 25^\circ\text{C}$)	P_D	64	W
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

Thermal Resistance

Parameter	Symbol	Value	Units
Thermal Resistance, Junction-to-Case, Steady-State	$R_{\theta JC}$	1.94	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient, Steady State ^{Note 4}	$R_{\theta JA}$	60	$^\circ\text{C}/\text{W}$

Notes:

1. The max drain current rating is package limited
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. $L = 0.5\text{ mH}$, $V_{DD} = 15\text{ V}$, $I_{AS} = 35\text{ A}$, $R_G = 25\text{ }\Omega$, Starting $T_J = 25\text{ }^\circ\text{C}$
4. Mount on 1 inch X 1 inch 2 oz FR-4 copper PCB
5. Pulse Test: Pulse width $\leq 300\text{ }\mu\text{s}$, Duty cycle $\leq 2\%$
6. Essentially independent of operating temperature

Electrical Characteristics($T_J = 25\text{ }^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units	
Static Characteristics							
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	40	-	-	V	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$	-	-	1	μA	
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$	-	-	± 100	nA	
Gate Threshold voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	1	1.5	2	V	
Drain-Source on-state resistance	$R_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 25\text{ A}$	-	1.1	1.3	mΩ	
		$V_{GS} = 4.5\text{ V}, I_D = 25\text{ A}$	-	1.6	2.0	mΩ	
Forward Transconductance ^{Note5}	G_{FS}	$V_{DS} = 2\text{ V}, I_D = 25\text{ A}$	-	90	-	S	
Dynamic Characteristics							
Input Capacitance	C_{iss}	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$ $f = 1\text{ MHz}$	-	3900	-	pF	
Output Capacitance	C_{oss}		-	1460	-	pF	
Reverse Transfer Capacitance	C_{rss}		-	32.9	-	pF	
Gate Resistance	R_g	$f = 1\text{ MHz}$	-	4.5	-	Ω	
Switching Characteristics							
Turn On Delay Time	$T_{D(on)}$	$V_{DD} = 20\text{ V}, I_D = 25\text{ A}$ $V_{GS} = 10\text{ V}, R_G = 4.7\text{ }\Omega$	-	11.8	-	ns	
Rise Time	T_r		-	30.2	-	ns	
Turn Off Delay Time	$T_{D(off)}$		-	78.7	-	ns	
Fall Time	T_f		-	37.4	-	ns	
Total Gate Charge	Q_g		$V_{DS} = 20\text{ V}, I_D = 25\text{ A}$ $V_{GS} = 10\text{ V}$	-	63.1	-	nC
Gate-Source Charge	Q_{gs}			-	10.4	-	nC
Gate-Drain Charge	Q_{gd}			-	12	-	nC
Drain-Source Diode Characteristics and Maximum Ratings							
Maximum Continuous Body-Diode Forward Current	I_S		-	-	176	A	
Maximum Pulsed Body-Diode Forward Current ^{Note1}	I_{SM}		-	-	550	A	
Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{ V}, I_S = 50\text{ A}$	-	0.84	-	V	
Reverse recovery time	T_{rr}	$I_S = 50\text{ A}, di/dt = 100\text{ A}/\mu\text{S}$	-	49.5	-	ns	
Reverse recovery charge	Q_{rr}		-	46.8	-	nC	

Electrical Characteristics Diagrams

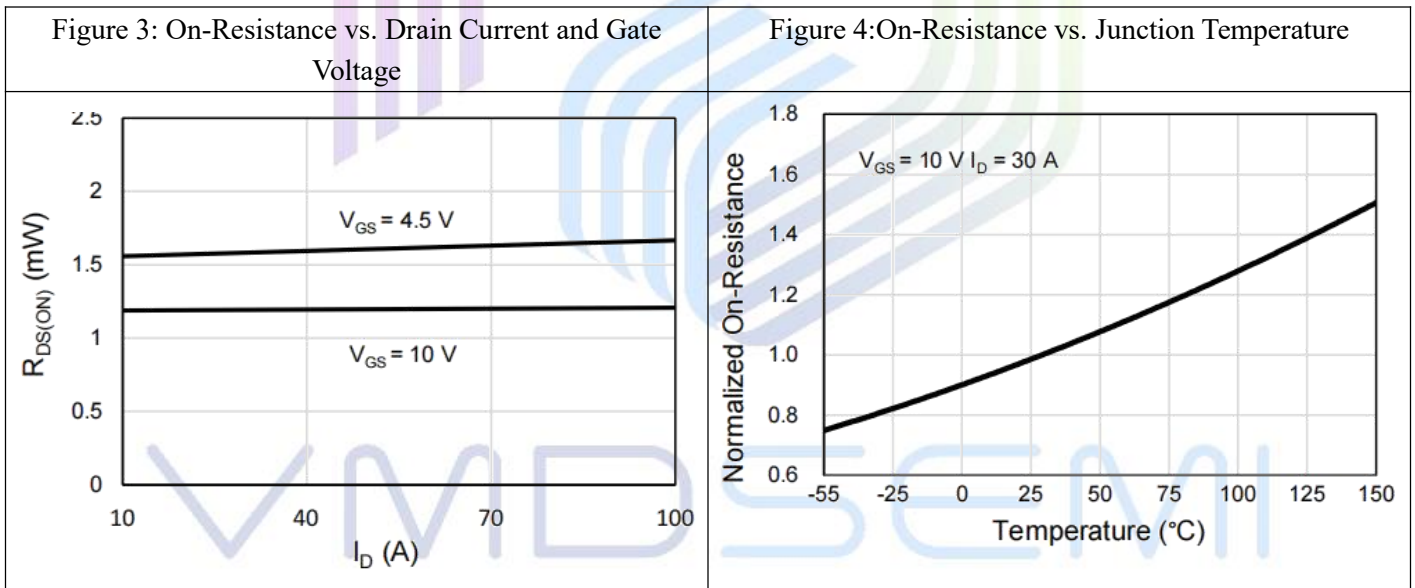
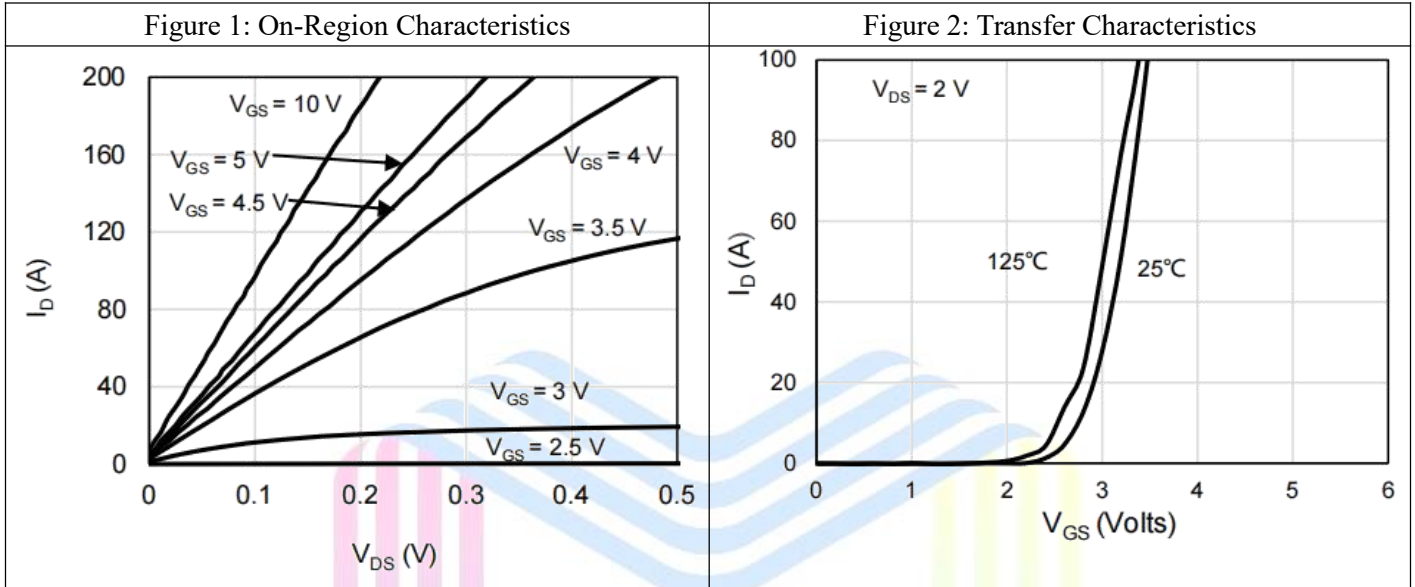


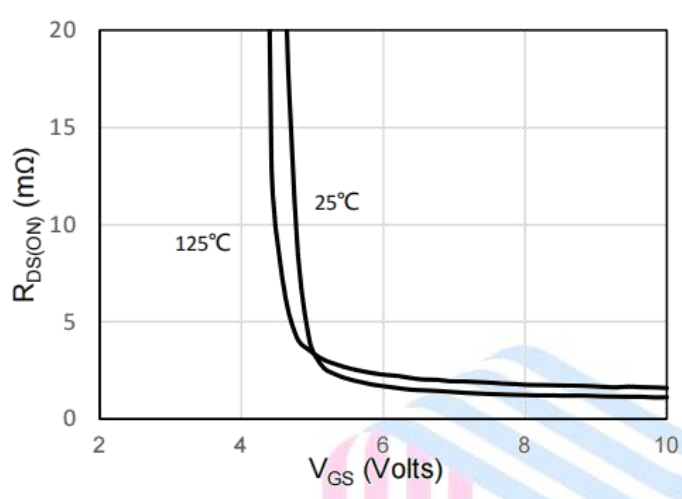
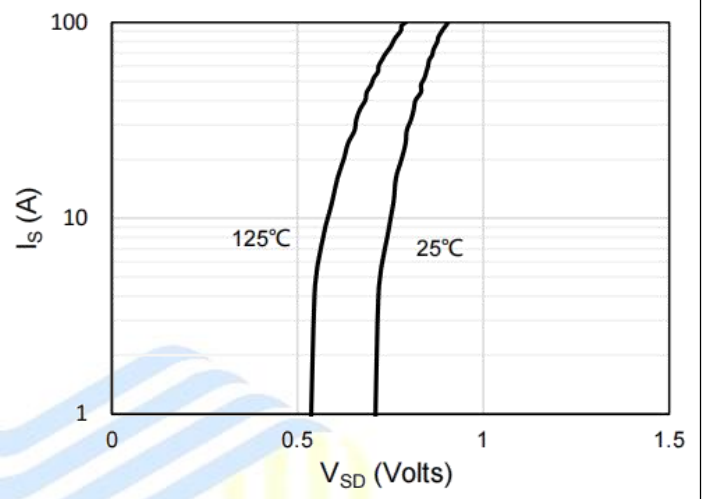
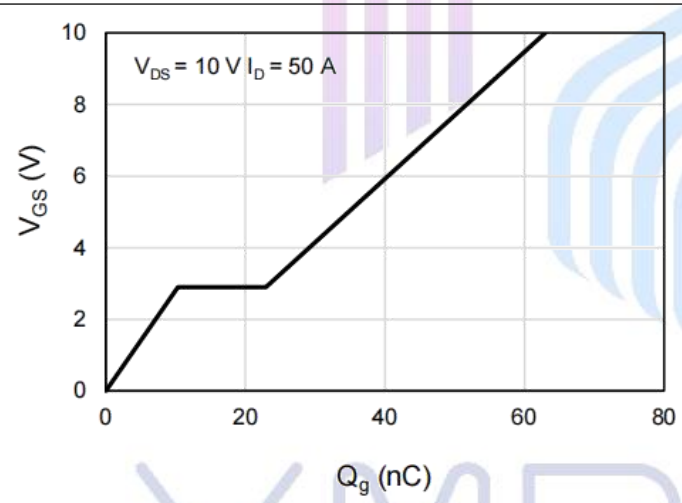
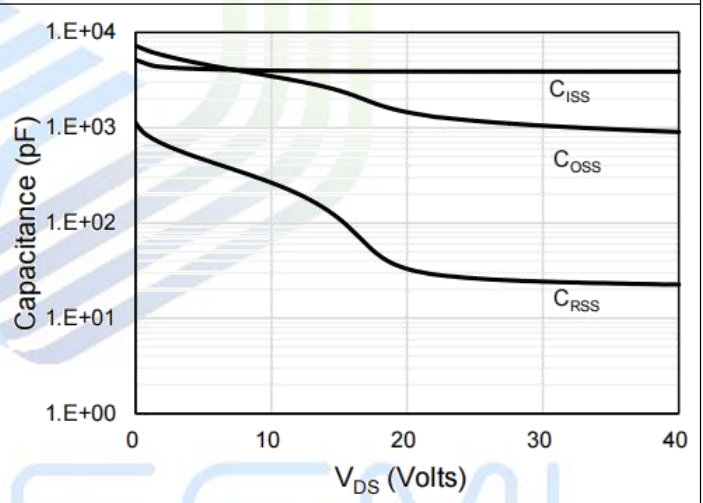
Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics


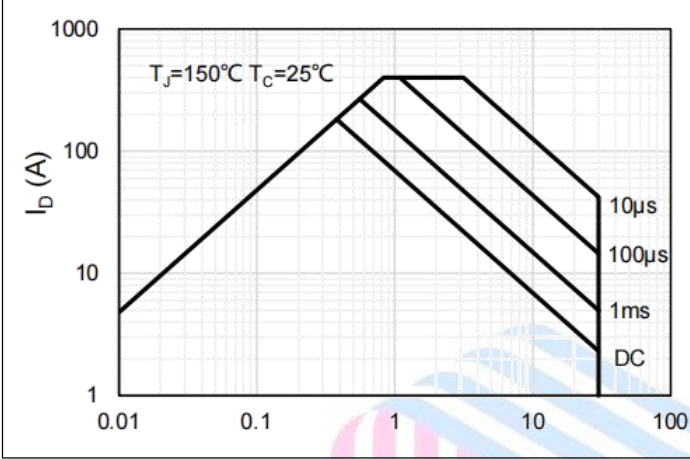
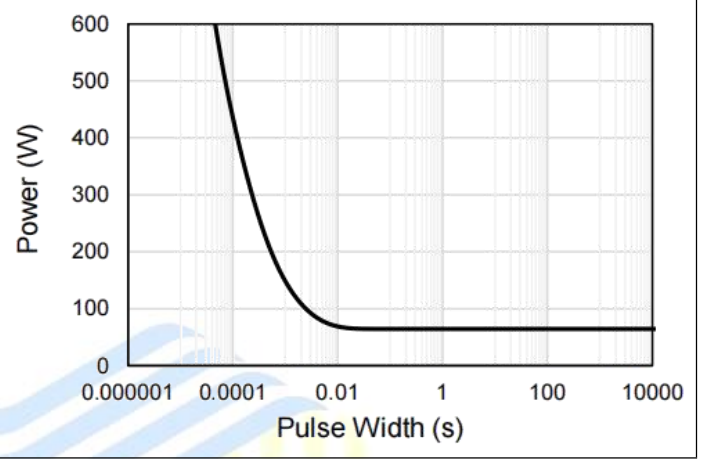
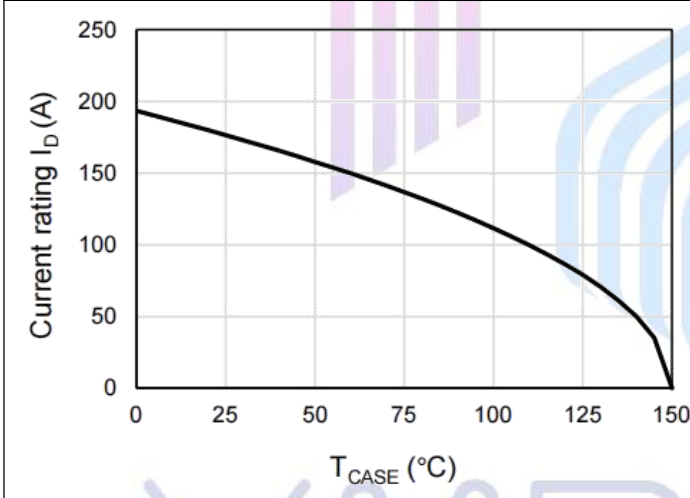
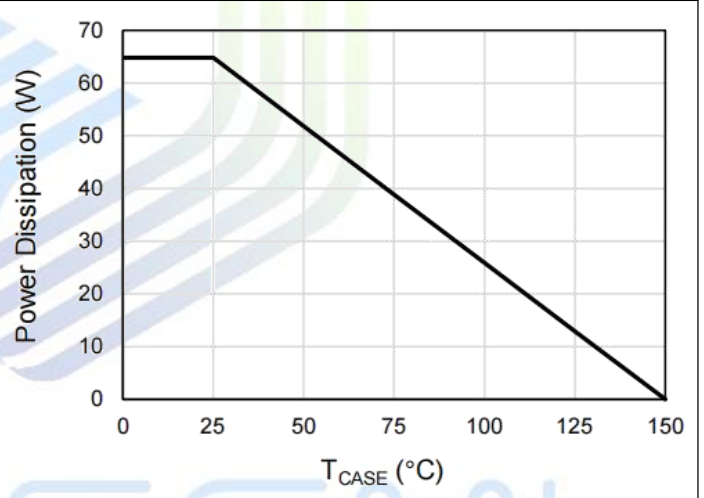
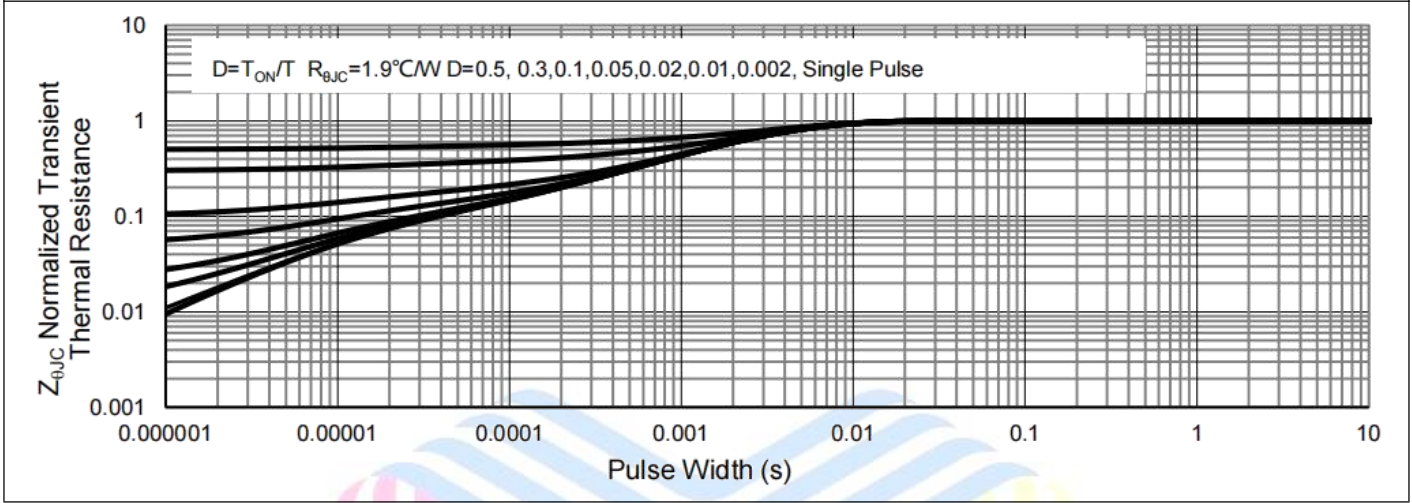
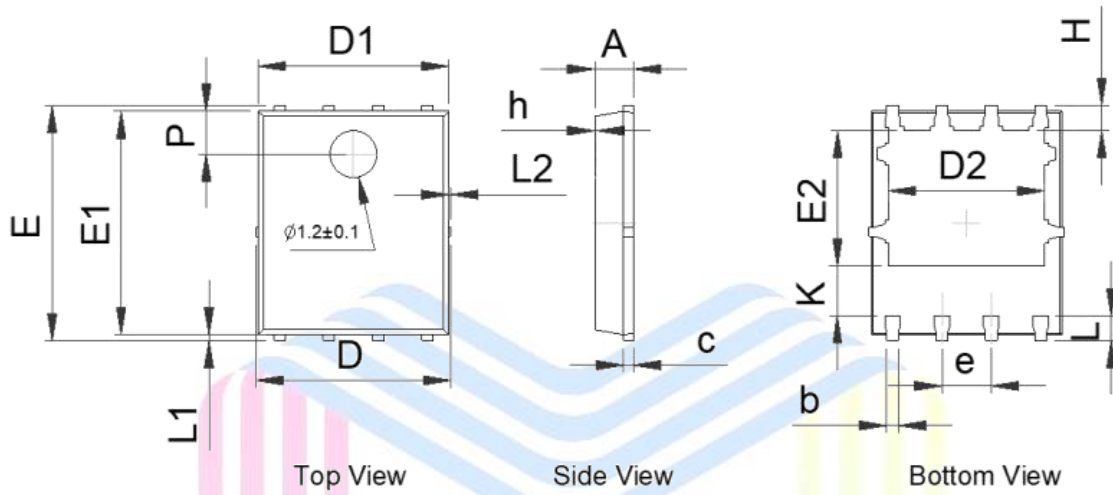
Figure 9: Maximum Forward Biased Safe Operating Area

Figure 10: Single Pulse Power Rating Junction-to-Case

Figure 11: Current De-rating

Figure 12: Power De-rating


Figure 13: Normalized Maximum Transient Thermal Impedance


Mechanical Dimensions

PDFN5x6 Package Information



SYMBOL	MIN	NOM	MAX
A	0.90	1.00	1.10
b	0.20	0.30	0.40
c	0.21	0.25	0.34
D	-	-	5.10
D1	4.80	4.90	5.00
D2	3.91	4.01	4.11
e	1.27 BSC		
E	5.90	6.00	6.10
E1	5.65	5.75	5.85
E2	3.375	3.475	3.575
H	0.55	0.65	0.75
h	-	-	0.10
K	1.20	-	-
L	0.55	0.65	0.75
L1	0.05	0.15	0.25
L2	-	-	0.12
θ	8°	10°	12°
P	1.00	1.10	1.20

Unit in mm

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